

HB56D25632 Series

4496203 0019099 T44 HIT2

262,144-Word x 32-Bit High Density Dynamic RAM Module

T-46-23-17

DESCRIPTION

The HB56D25632B is a 256k x 32 dynamic RAM module, mounted 8 pieces of 1 Mbit DRAM (HM514256JP) sealed in SOJ package. An outline of the HB56D25632B is 72-pin single in-line package. Therefore, the HB56D25632B makes high density mounting possible without surface mount technology. The HB56D25632B provides common data inputs and outputs. Decoupling capacitors are mounted beneath each SOJ.

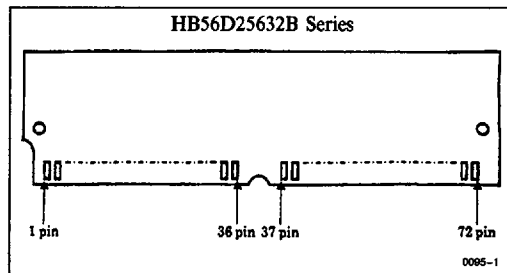
FEATURES

- 72-pin Single In-line Package
 - Lead Pitch 1.27mm
- Single 5V ($\pm 5\%$) Supply
- High Speed
 - Access Time 60 ns/70 ns/80 ns/100 ns/120 ns (max)
- Low Power Dissipation
 - Active Mode 3.78W/3.36W/2.772W/2.31W/1.974W (max)
 - Standby Mode 84 mW (max)
- Fast Page Mode Capability
- 512 Refresh Cycle/8 ms
- 2 Variations of Refresh
 - RAS Only Refresh
 - CAS Before RAS Refresh
- TTL Compatible

ORDERING INFORMATION

Part No.	Access Time	Package
HB56D25632B-6A	60 ns	72-pin SIP Socket Type
HB56D25632B-7A	70 ns	
HB56D25632B-8A	80 ns	
HB56D25632B-10A	100 ns	
HB56D25632B-12A	120 ns	

PIN OUT



Pin No.	Pin Name	Pin No.	Pin Name	Pin No.	Pin Name	Pin No.	Pin Name
1	V _{SS}	19	NC	37	NC	55	DQ11
2	DQ0	20	DQ4	38	NC	56	DQ27
3	DQ16	21	DQ20	39	V _{SS}	57	DQ12
4	DQ1	22	DQ5	40	CAS ₀	58	DQ28
5	DQ17	23	DQ21	41	CAS ₂	59	V _{CC}
6	DQ2	24	DQ6	42	CAS ₃	60	DQ29
7	DQ18	25	DQ22	43	CAS ₁	61	DQ13
8	DQ3	26	DQ7	44	RAS ₀	62	DQ30
9	DQ19	27	DQ23	45	NC	63	DQ14
10	V _{CC}	28	A7	46	NC	64	DQ31
11	NC	29	NC	47	WE	65	DQ15
12	A0	30	V _{CC}	48	NC	66	NC
13	A1	31	A8	49	DQ8	67	V _{SS}
14	A2	32	NC	50	DQ24	68	NC
15	A3	33	NC	51	DQ9	69	T.B.D.
16	A4	34	RAS ₂	52	DQ25	70	T.B.D.
17	A5	35	NC	53	DQ10	71	NC
18	A6	36	NC	54	DQ26	72	V _{SS}

PIN DESCRIPTION

Pin Name	Function
A ₀ -A ₈	Address Input
A ₀ -A ₈	Refresh Address Input
DQ ₀ -DQ ₃₁	Data-in/Data-out
CAS ₀ -CAS ₃	Column Address Strobe
RAS ₀ -RAS ₂	Row Address Strobe
WE	Read/Write Enable
V _{CC}	Power (+ 5V)
V _{SS}	Ground
NC	No Connection

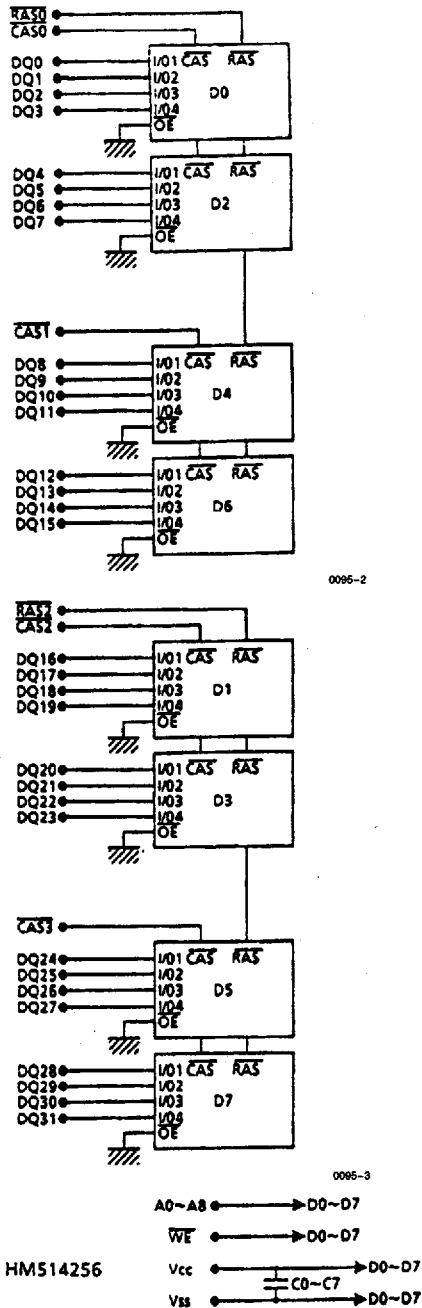
HITACHI/ LOGIC/ARRAYS/MEM 51E D



■ BLOCK DIAGRAM

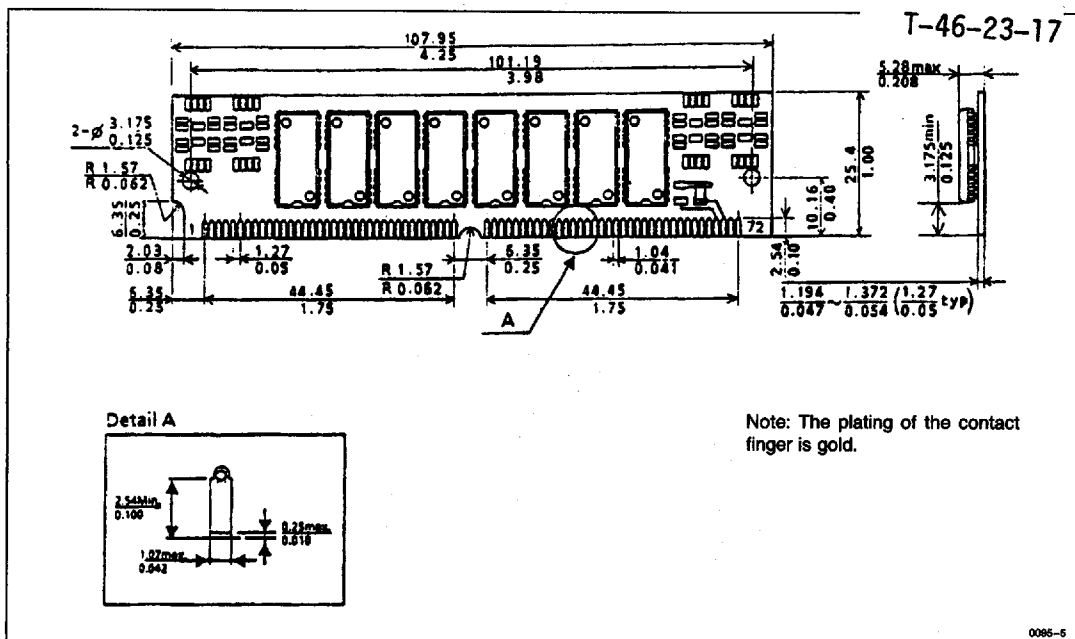
HITACHI/ LOGIC/ARRAYS/MEM

T-46-23-17



■ PHYSICAL OUTLINE

HITACHI/ LOGIC/ARRAYS/MEM

Unit: $\frac{\text{mm}}{\text{inch}}$ 

■ ABSOLUTE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Voltage on Any Pin Relative to V_{SS}	(Input) V_{in}	-1.0 to +7.0	V
	(Output) V_{out}	-1.0 to +7.0	V
Supply Voltage Relative to V_{SS}	V_{CC}	-1.0 to +7.0	V
Short Circuit Output Current	I_{out}	50	mA
Power Dissipation	P_T	8	W
Operating Temperature	T_{opr}	0 to +70	°C
Storage Temperature	T_{stg}	-55 to +125	°C

■ ELECTRICAL CHARACTERISTICS

• Recommended DC Operating Conditions ($T_A = 0$ to +70°C)

Parameter	Symbol	Min	Typ	Max	Unit	Note
Supply Voltage	V_{SS}	0	0	0	V	
	V_{CC}	4.75	5.0	5.25	V	1
Input High Voltage	V_{IH}	2.4	—	5.5	V	1
Input Low Voltage	V_{IL}	-1.0	—	0.8	V	1

Note 1. All voltage referenced to V_{SS} .

• DC Electrical Characteristics ($T_A = 0$ to $+70^\circ\text{C}$, $V_{CC} = 5\text{V} \pm 5\%$, $V_{SS} = 0\text{V}$)

T-46-23-17

Parameter	Symbol	-6A		-7A		-8A		-10A		-12A		Unit	Test Condition	Note
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max			
Operating Current	I_{CC1}	—	720	—	640	—	528	—	440	—	376	mA	$t_{RC} = \text{Min}$	1, 2
Standby Current	I_{CC2}	—	16	—	16	—	16	—	16	—	16	mA	TTL Interface RAS, CAS = V_{IH} $D_{out} = \text{High-Z}$	
		—	8	—	8	—	8	—	8	—	8	mA	CMOS Interface RAS, CAS $\geq V_{CC} - 0.2\text{V}$ $D_{out} = \text{High-Z}$	
RAS Only Refresh Current	I_{CC3}	—	720	—	640	—	528	—	440	—	376	mA	$t_{RC} = \text{Min}$	2
Standby Current	I_{CC5}	—	40	—	40	—	40	—	40	—	40	mA	RAS = V_{IH} CAS = V_{IL} $D_{out} = \text{Enable}$	1
CAS Before RAS Refresh Current	I_{CC6}	—	720	—	640	—	528	—	440	—	376	mA	$t_{RC} = \text{Min}$	
Page Mode Current	I_{CC7}	—	720	—	640	—	440	—	440	—	376	mA	$t_{PC} = \text{Min}$	1, 3
Input Leakage Current	I_{LI}	-10	10	-10	10	-10	10	-10	10	-10	10	μA	$0\text{V} \leq V_{in} \leq 7\text{V}$	
Output Leakage Current	I_{LO}	-10	10	-10	10	-10	10	-10	10	-10	10	μA	$0\text{V} \leq V_{out} \leq 7\text{V}$ $D_{out} = \text{Disable}$	
Output High Voltage	V_{OH}	2.4	V_{CC}	2.4	V_{CC}	2.4	V_{CC}	2.4	V_{CC}	2.4	V_{CC}	V	High $I_{out} = -5\text{mA}$	
Output Low Voltage	V_{OL}	0	0.4	0	0.4	0	0.4	0	0.4	0	0.4	V	Low $I_{out} = 4.2\text{mA}$	

Notes: 1. I_{CC} depends on output load condition when the device is selected, I_{CC} max is specified at the output open condition.2. Address can be changed less than three times while RAS = V_{IL} .3. Address can be changed once or less while CAS = V_{IH} .• Capacitance ($T_A = 25^\circ\text{C}$, $V_{CC} = 5\text{V} \pm 5\%$)

Parameter	Symbol	Typ	Max	Unit	Note
Input Capacitance (Address)	C_{I1}	—	68	pF	1
Input Capacitance ($\overline{\text{WE}}$)	C_{I2}	—	76	pF	1
Input Capacitance (RAS)	C_{I3}	—	43	pF	1
Input Capacitance (CAS)	C_{I4}	—	29	pF	1
Output Capacitance (DQ0-DQ31)	$C_{L/O}$	—	17	pF	1, 2

Notes: 1. Capacitance measured with Boonton Meter or effective capacitance measuring method.

2. CAS = V_{IH} to disable D_{out} .• AC Characteristics ($T_A = 0$ to $+70^\circ\text{C}$, $V_{CC} = 5\text{V} \pm 5\%$, $V_{SS} = 0\text{V}$)^{1, 12}

Read, Write and Refresh Cycle (Common Parameters)

Parameter	Symbol	-6A		-7A		-8A		-10A		-12A		Unit	Note
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max		
Random Read or Write Cycle Time	t_{RC}	125	—	140	—	160	—	190	—	220	—	ns	
RAS Precharge Time	t_{RP}	55	—	60	—	70	—	80	—	90	—	ns	
RAS Pulse Width	t_{RAS}	60	10000	70	10000	80	10000	100	10000	120	10000	ns	
CAS Pulse Width	t_{CAS}	20	10000	20	10000	25	10000	25	10000	30	10000	ns	
Row Address Setup Time	t_{ASR}	0	—	0	—	0	—	0	—	0	—	ns	
Row Address Hold Time	t_{RAH}	10	—	10	—	12	—	15	—	15	—	ns	

HITACHI/ LOGIC/ARRAYS/MEM



Read, Write and Refresh Cycle (Common Parameters) (continued)

Parameter	Symbol	-6A		-7A		-8A		-10A		-12A		Unit	Note
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max		
Column Address Setup Time	t_{ASC}	0	—	0	—	0	—	0	—	0	—	ns	
Column Address Hold Time	t_{CAH}	15	—	15	—	20	—	20	—	25	—	ns	
RAS to CAS Delay Time	t_{RCD}	20	40	20	50	22	55	25	75	25	90	ns	8
RAS to Column Address Delay Time	t_{RAD}	15	30	15	35	17	40	20	55	20	65	ns	9
RAS Hold Time	t_{RSH}	20	—	20	—	25	—	25	—	30	—	ns	
CAS Hold Time	t_{CSH}	60	—	70	—	80	—	100	—	120	—	ns	
CAS to RAS Precharge Time	t_{CRP}	10	—	10	—	10	—	10	—	10	—	ns	
Transition Time (Rise and Fall)	t_T	3	50	3	50	3	50	3	50	3	50	ns	7
Refresh Period	t_{REF}	—	8	—	8	—	8	—	8	—	8	ns	15

Read Cycle

HITACHI/ LOGIC/ARRAYS/MEM

Parameter	Symbol	-6A		-7A		-8A		-10A		-12A		Unit	Note
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max		
Access Time from RAS	t_{RAC}	—	60	—	70	—	80	—	100	—	120	ns	2, 3
Access Time from CAS	t_{CAC}	—	20	—	20	—	25	—	25	—	30	ns	3, 4
Access Time from Address	t_{AA}	—	30	—	35	—	40	—	45	—	55	ns	3, 5
Read Command Setup Time	t_{RCS}	0	—	0	—	0	—	0	—	0	—	ns	
Read Command Hold Time to CAS	t_{RCH}	0	—	0	—	0	—	0	—	0	—	ns	
Read Command Hold Time to RAS	t_{RRH}	10	—	10	—	10	—	10	—	10	—	ns	
Column Address to RAS Lead Time	t_{RAL}	30	—	35	—	40	—	45	—	55	—	ns	
Output Buffer Turn-off Time	t_{OFF}	—	20	—	20	—	20	—	25	—	30	ns	6

Write Cycle

Parameter	Symbol	-6A		-7A		-8A		-10A		-12A		Unit	Note
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max		
Write Command Setup Time	t_{WCS}	0	—	0	—	0	—	0	—	0	—	ns	10
Write Command Hold Time	t_{WCH}	15	—	15	—	20	—	20	—	25	—	ns	
Write Command Pulse Width	t_{WP}	10	—	10	—	15	—	15	—	20	—	ns	
Data-in Setup Time	t_{DS}	0	—	0	—	0	—	0	—	0	—	ns	11
Data-in Hold Time	t_{DH}	15	—	15	—	20	—	20	—	25	—	ns	11

Refresh Cycle

Parameter	Symbol	-6A		-7A		-8A		-10A		-12A		Unit	Note
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max		
CAS Setup Time (CAS Before RAS Refresh Cycle)	t_{CSR}	10	—	10	—	10	—	10	—	10	—	ns	
CAS Hold Time (CAS Before RAS Refresh Cycle)	t_{CHR}	15	—	15	—	20	—	20	—	25	—	ns	
RAS Precharge to CAS Hold Time	t_{RPC}	10	—	10	—	10	—	10	—	10	—	ns	



Fast Page Mode Cycle

Parameter	Symbol	-6A		-7A		-8A		-10A		-12A		Unit	Note
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max		
Fast Page Mode Cycle Time	t_{PC}	45	—	50	—	55	—	55	—	65	—	ns	
Fast Page Mode CAS Precharge Time	t_{CP}	10	—	10	—	10	—	15	—	20	—	ns	
Fast Page Mode RAS Pulse Width	t_{RASC}	—	100000	—	100000	—	100000	—	100000	—	100000	ns	12
Access Time from CAS Precharge	t_{ACP}	—	40	—	45	—	50	—	50	—	60	ns	13
RAS Hold Time from CAS Precharge	t_{RHCP}	40	—	45	—	50	—	50	—	60	—	ns	

- Notes:
1. AC measurements assume $t_T = 5$ ns.
 2. Assumes that $t_{RCD} \leq t_{RCD}(\text{max})$ and $t_{RAD} \leq t_{RAD}(\text{max})$. If t_{RCD} or t_{RAD} is greater than the maximum recommended value shown in this table, t_{RAC} exceeds the value shown.
 3. Measured with a load circuit equivalent to 2 TTL loads and 100 pF.
 4. Assumes that $t_{RCD} \geq t_{RCD}(\text{max})$, $t_{RAD} \leq t_{RAD}(\text{max})$.
 5. Assumes that $t_{RCD} \leq t_{RCD}(\text{max})$, $t_{RAD} \geq t_{RAD}(\text{max})$.
 6. $t_{OFF}(\text{max})$ is defined as the time at which the output achieves the open circuit condition and is not referenced to output voltage levels.
 7. $V_{IH}(\text{min})$ and $V_{IL}(\text{max})$ are reference levels for measuring timing of input signals. Also, transition times are measured between V_{IH} and V_{IL} .
 8. Operation with the $t_{RCD}(\text{max})$ limit insures that $t_{RAC}(\text{max})$ can be met, $t_{RCD}(\text{max})$ is specified as a reference point only, if t_{RCD} is greater than the specified $t_{RCD}(\text{max})$ limit, then access time is controlled exclusively by t_{CAC} .
 9. Operation with the $t_{RAD}(\text{max})$ limit insures that $t_{RAC}(\text{max})$ can be met, $t_{RAD}(\text{max})$ is specified as a reference point only, if t_{RAD} is greater than the specified $t_{RAD}(\text{max})$ limit, then access time is controlled exclusively by t_{AA} .
 10. Early write cycle only ($t_{WCS} \geq t_{WCS}(\text{min})$).
 11. These parameters are referenced to $\overline{\text{CAS}}$ leading edge in an early write cycle.
 12. An initial pause of 100 μs is required after power up followed by a minimum of eight initialization cycles (any combination of cycles containing $\overline{\text{RAS}}$ clock such as $\overline{\text{RAS}}$ only refresh).
 13. t_{RASC} is determined by $\overline{\text{RAS}}$ pulse width in fast page mode cycles.
 14. Access time is determined by the longer of t_{AA} or t_{CAC} or t_{ACP} .
 15. t_{REF} is determined by 512 refresh cycles.

HITACHI/ LOGIC/ARRAYS/MEM

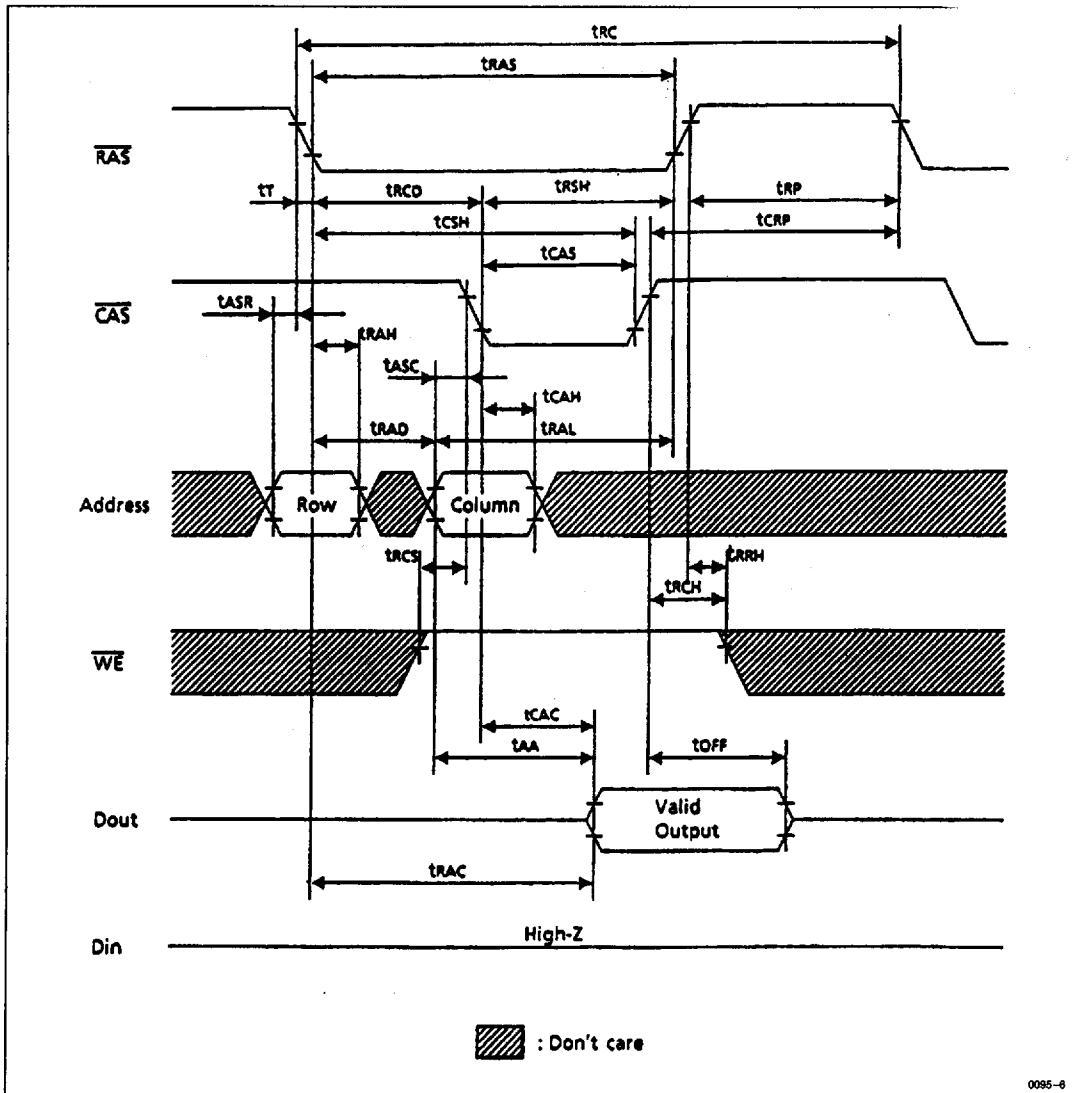


■ TIMING WAVEFORM

• Read Cycle

HITACHI/ LOGIC/ARRAYS/MEM

T-46-23-17

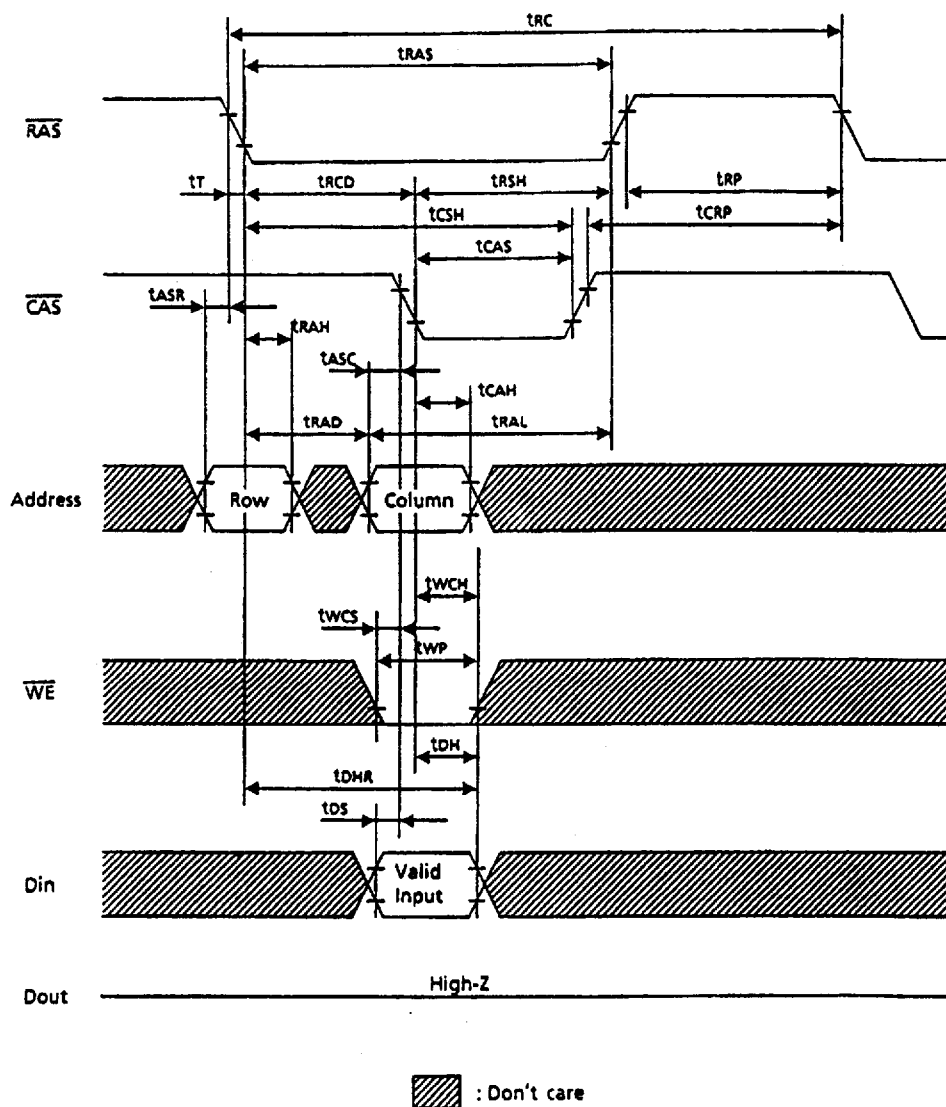


0095-6



■ Early Write Cycle

HITACHI/ LOGIC/ARRAYS/MEM

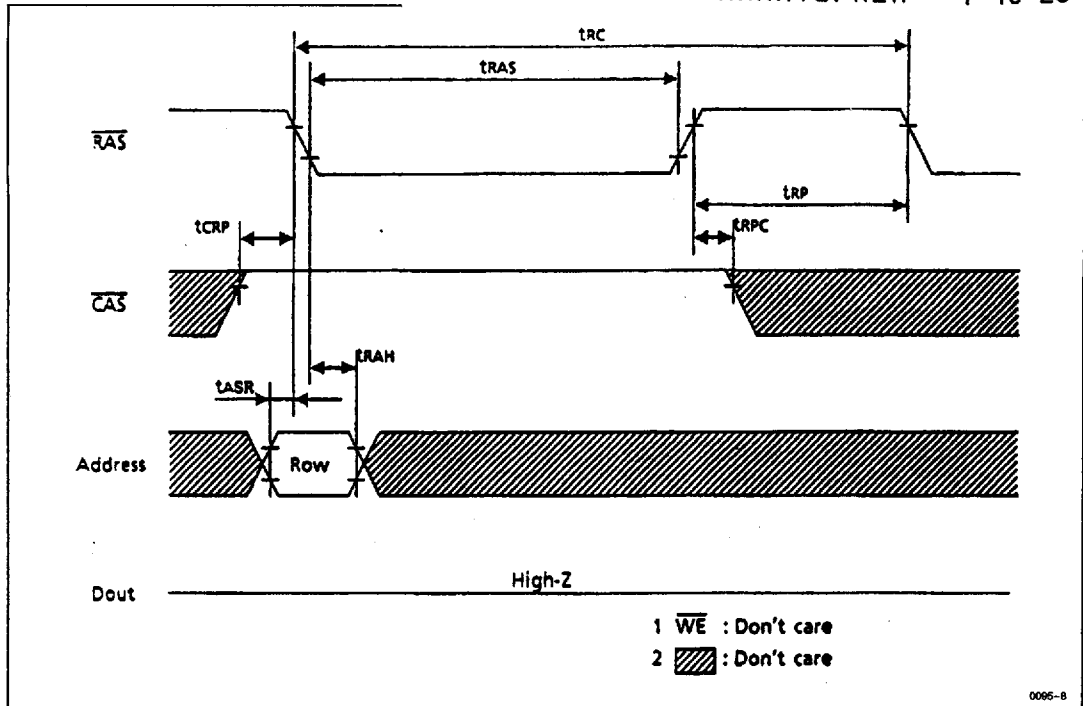


0095-7

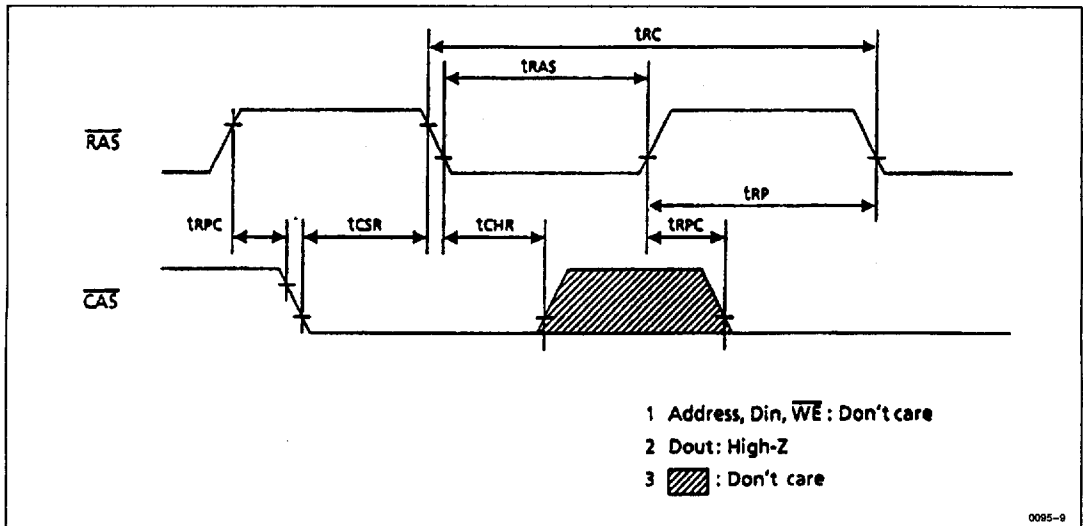


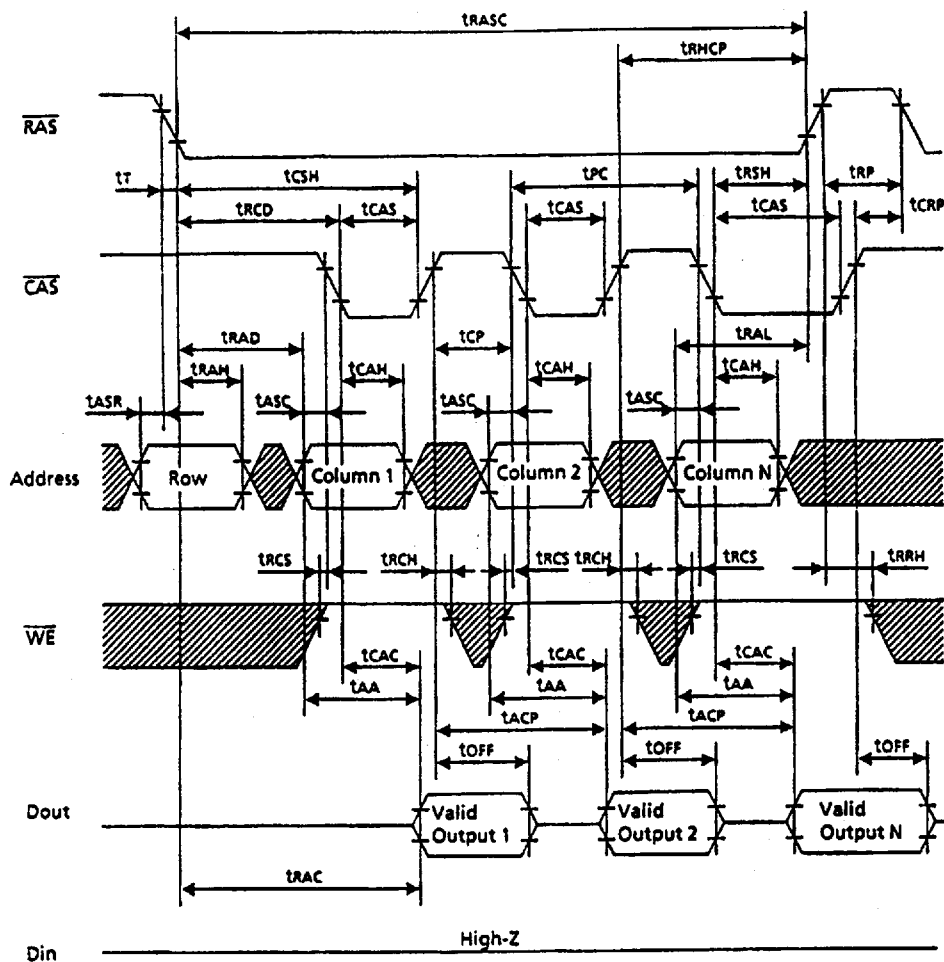
• RAS Only Refresh Cycle

HITACHI/ LOGIC/ARRAYS/MEM T-46-23-17



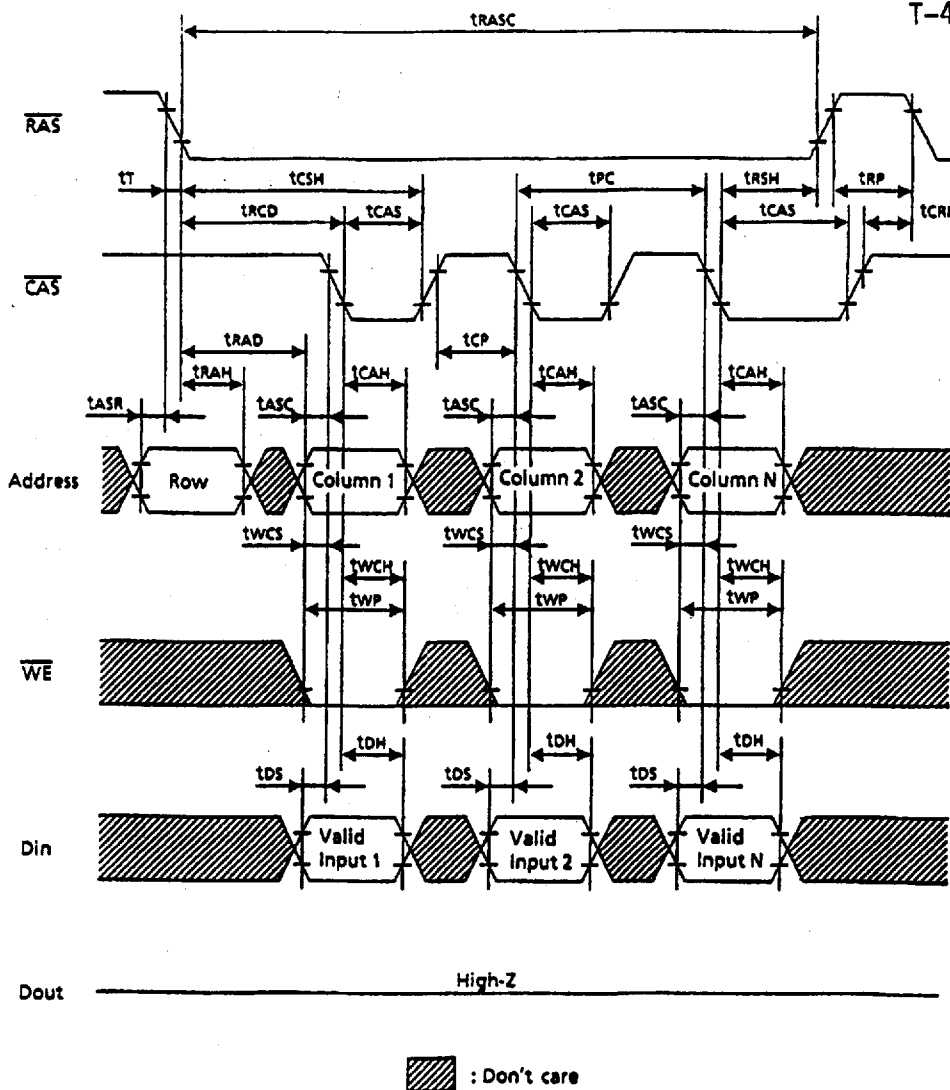
• CAS Before RAS Refresh Cycle





 : Don't care

0095-10



0095-11

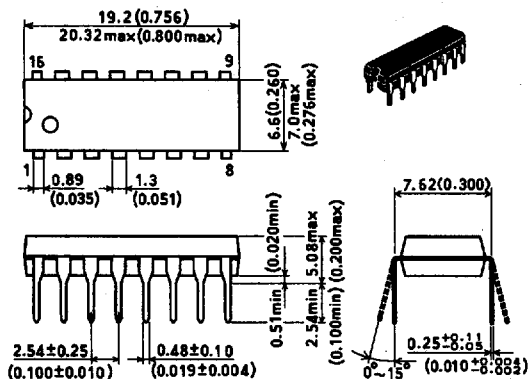


T-90-20

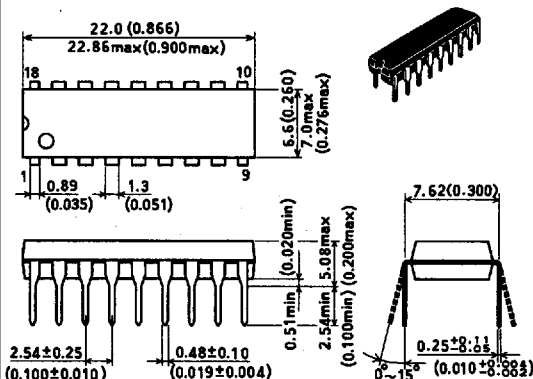
Unit: mm (inch) Scale 3/2

• Dual-in-line Plastic

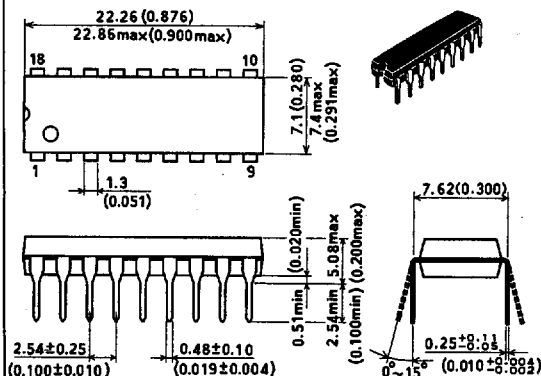
• DP-16B



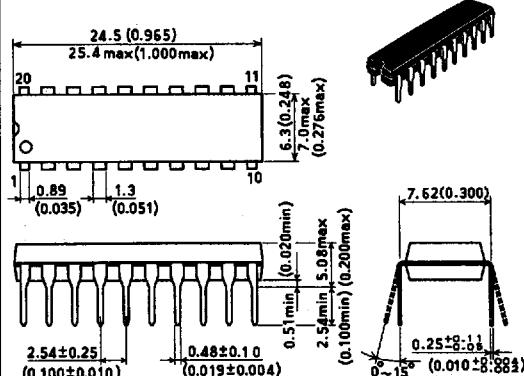
• DP-18B



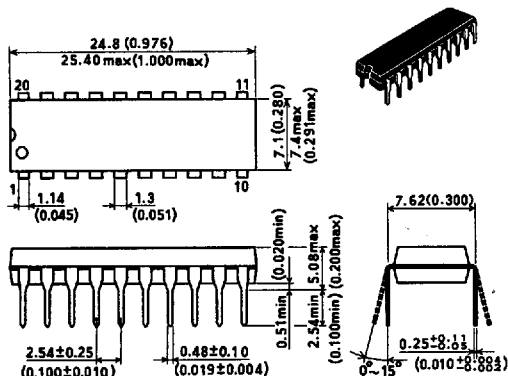
• DP-18C



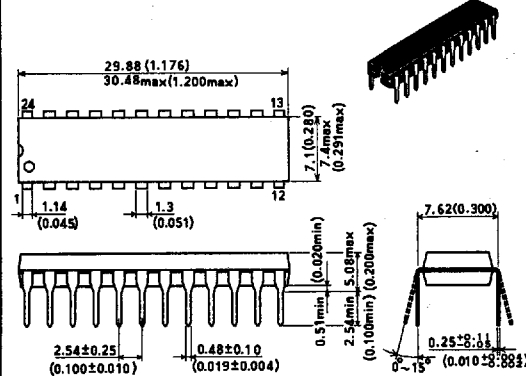
• DP-20N



• DP-20NA



• DP-20NC

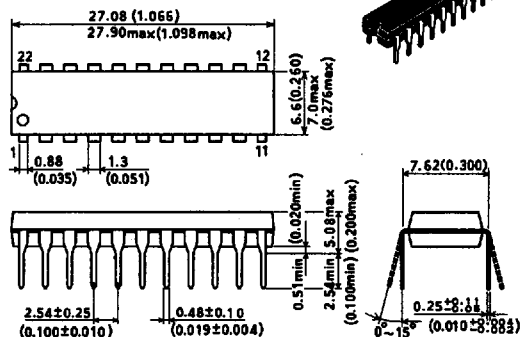


• Dual-In-line Plastic

HITACHI/ LOGIC/ARRAYS/MEM

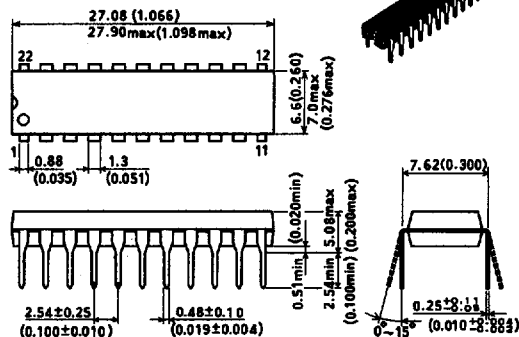
Unit: mm (inch) Scale 3/2

• DP-22N

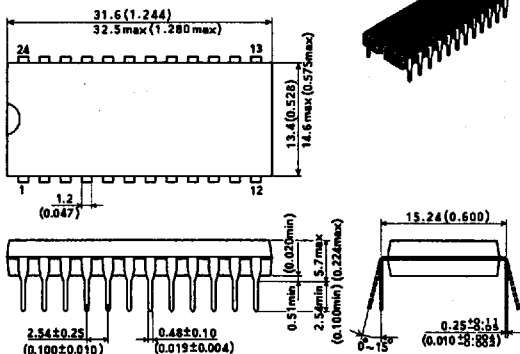


• DP-22NB

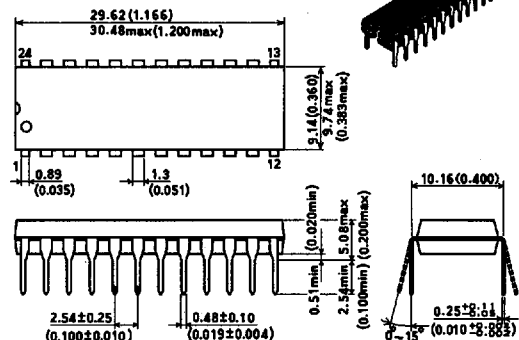
T-90-20



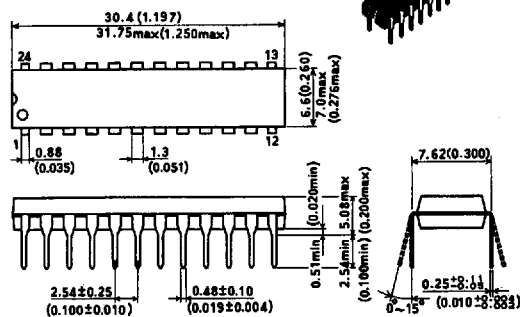
• DP-24



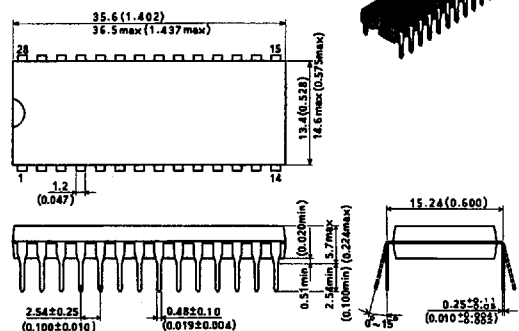
• DP-24A



• DP-24N



• DP-28

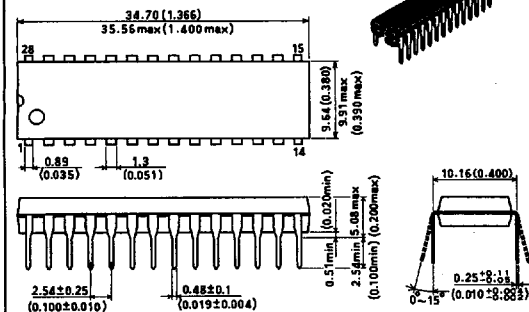


• Dual-in-line Plastic

HITACHI/ LOGIC/ARRAYS/MEM

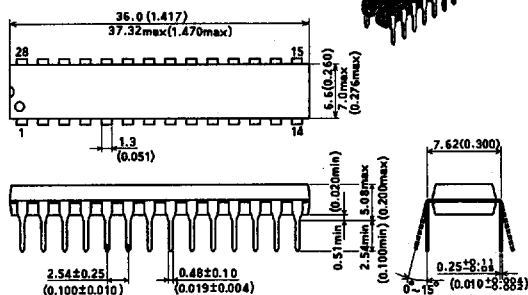
Unit: mm (inch) Scale 3/2

• DP-28C

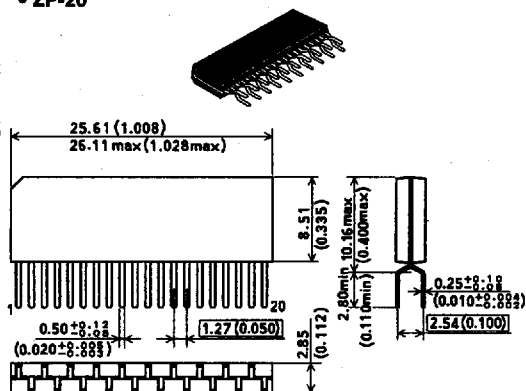


• DP-28N

T-90-20

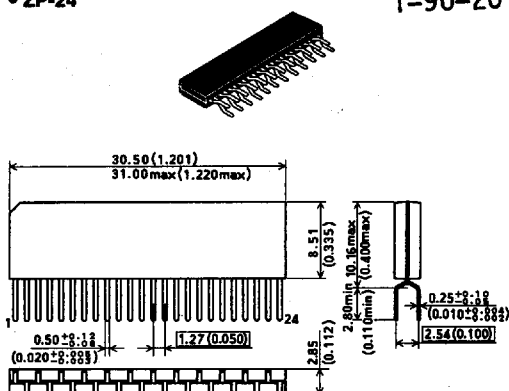


• ZP-20

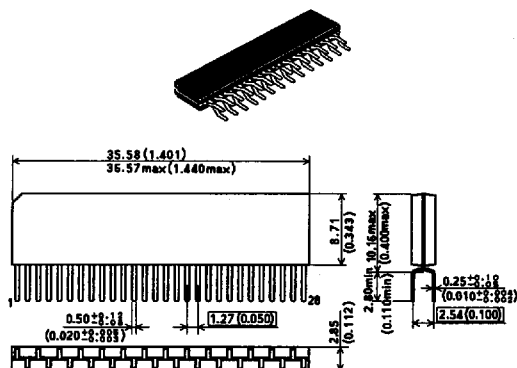


• ZP-24

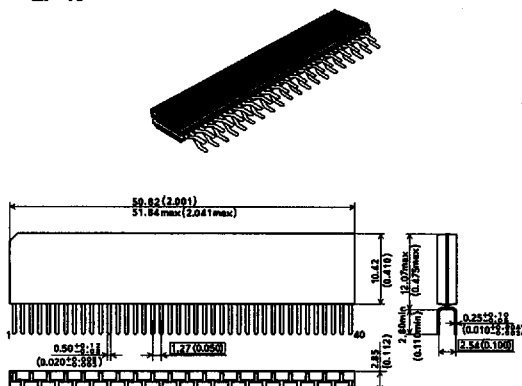
T-90-20



• ZP-28



• ZP-40



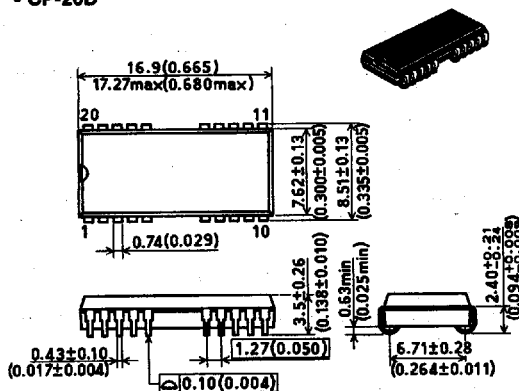
• Flat Package (J-bend Leads)

HITACHI/ LOGIC/ARRAYS/MEM

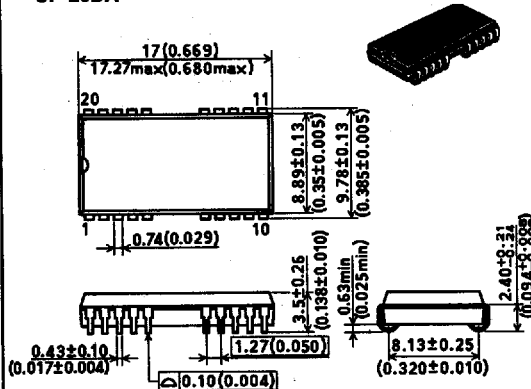
Unit: mm (inch) Scale 3/2

T-90-20

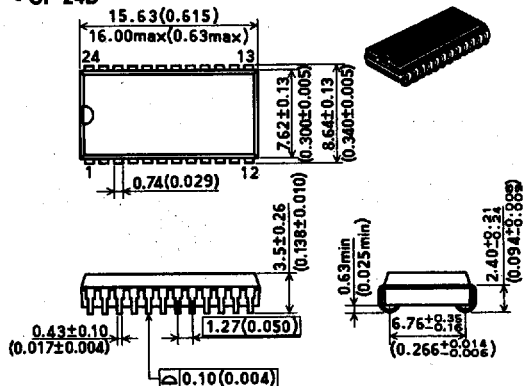
• CP-20D



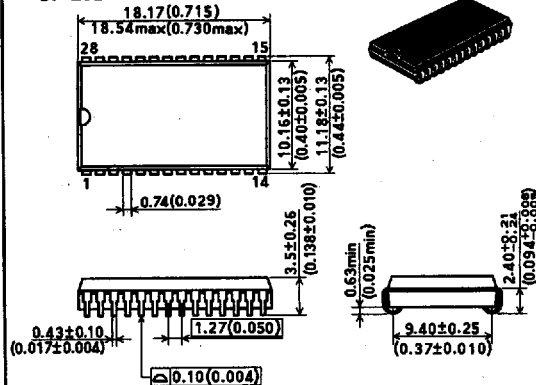
• CP-20DA



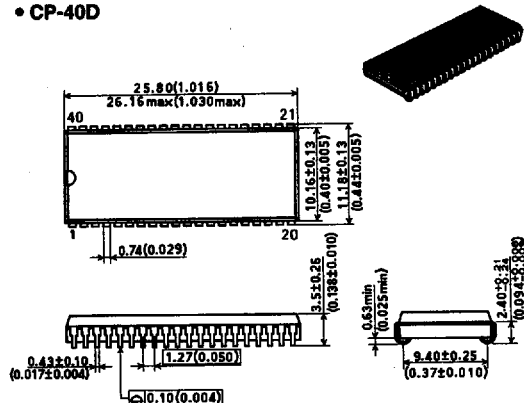
• CP-24D



• CP-28D



• CP-40D

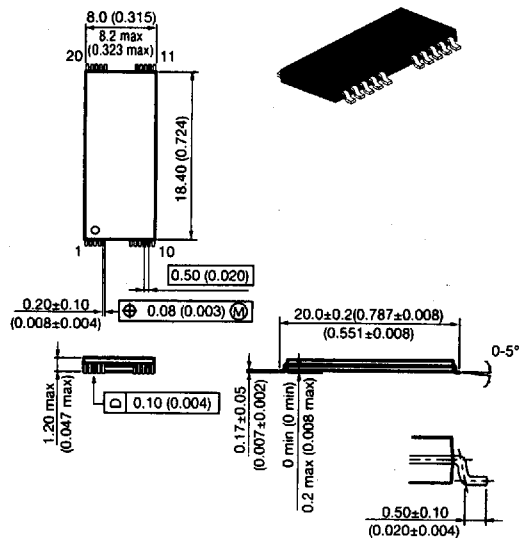


• TSOP (Thin Small Outline Package)

HITACHI/ LOGIC/ARRAYS/MEM

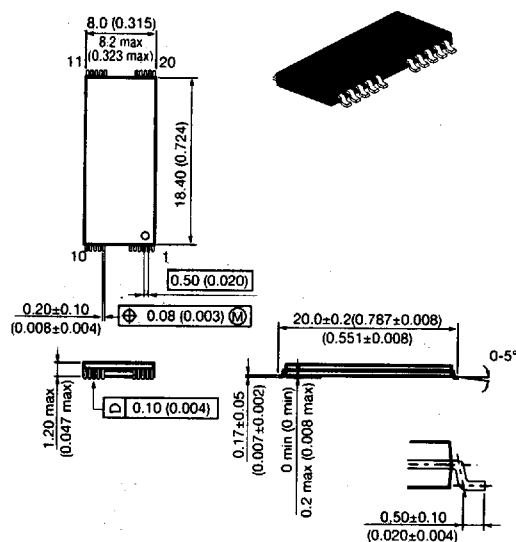
Unit: mm (inch) Scale 3/2

• TFP-20DA

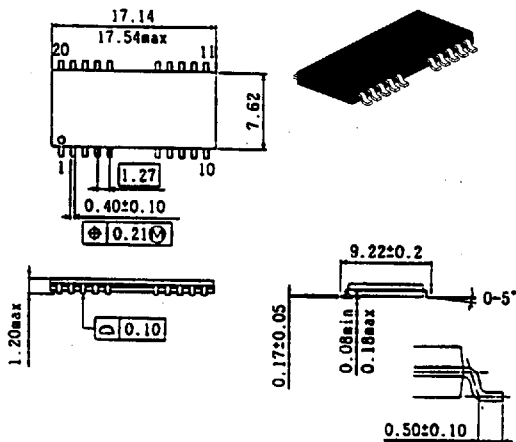


• TFP-20DAR

T-90-20



• TTP-20D



• TTP-20DR

